

<b>Notice of References Cited</b>	Application/Control No. 10/691,869	Applicant(s)/Patent Under Reexamination SIEPMANN, JAMES P.	
	Examiner Phillip Nguyen	Art Unit 2828	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,987,044 A	11-1999	Odagawa et al.	372/38.02
*	B	US-5,991,325 A	11-1999	Ohtomo et al.	372/69
*	C	US-6,075,801 A	06-2000	Tamanuki et al.	372/46.01
*	D	US-6,192,060 B1	02-2001	Kobayashi, Ippei	372/38.01
*	E	US-5,561,676 A	10-1996	Goldberg, Lew	372/18
*	F	US-6,256,329 B1	07-2001	Ishizuka et al.	372/38.02
*	G	US-5,912,911	06-1999	Usami et al.	372/25
*	H	US-5,825,798	10-1998	Momiuchi et al.	372/75
*	I	US-5,177,752	01-1993	Ohya et al.	372/22
*	J	US-6,091,747	07-2000	Morita et al.	372/38.02
*	K	US-6,078,601	06-2000	Smith, David F.	372/29.014
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.